

Resource Summary Report

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Bruker: DektakXT Stylus Profiler

RRID:SCR_028211

Type: Tool

Proper Citation

Bruker: DektakXT Stylus Profiler (RRID:SCR_028211)

Resource Information

URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028211.pdf

Proper Citation: Bruker: DektakXT Stylus Profiler (RRID:SCR_028211)

Description: Advanced, stylus-based surface profiler used for high-precision, 2D and 3D surface topography measurements, including step height, surface roughness, and waviness. System measures roughness in the nanometer range. It provides a step-height repeatability of 5???. It uses a diamond-tip stylus to physically trace samples, offering sub-nanometer vertical resolution and high repeatability.

Synonyms: , DektakXT Stylus Surface Profiler, Surface Profilometer (DektakXT)

Resource Type: instrument resource

Keywords: surface profilometer, thin film metrology, roughness measurement, step height analysis

Availability: Commercially available

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028211.pdf

Resource Name: Bruker: DektakXT Stylus Profiler

Resource ID: SCR_028211

Alternate IDs: Model_Number_Bruker_DektakXT

Record Creation Time: 20260327T054534+0000

Record Last Update: 20260829T183523+0000

Ratings and Alerts

No rating or validation information has been found for Bruker: DektakXT Stylus Profiler.

No alerts have been found for Bruker: DektakXT Stylus Profiler.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.